

(PREVIEW)

IS 14901 (Part 1) : 2010
IEC 60747-1 : 2006

Indian Standard

SEMICONDUCTOR DEVICES — DISCRETE DEVICES AND INTEGRATED CIRCUITS

PART 1 GENERAL

1 Scope

This part of IEC 60747 gives the general requirements applicable to the discrete semiconductor devices and integrated circuits covered by the other parts of IEC 60747 and IEC 60748 (see Annex A).

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60027 (all parts), *Letter symbols to be used in electrical technology*

IEC 60050-521, *International Electrotechnical Vocabulary (IEV) - Part 521: Semiconductor devices and integrated circuits*

IEC 60050-702, *International Electrotechnical Vocabulary (IEV) - Part 702: Oscillations, signals and related devices*

IEC 60068 (all parts), *Environmental testing*

IEC 60191-2, *Mechanical standardization of semiconductor devices - Part 2 : Dimensions*

IEC 60747 (all parts), *Semiconductor devices*

IEC 60748 (all parts), *Semiconductor devices - Integrated circuits*

IEC 60749-26, *Semiconductor devices - Mechanical and climatic test methods - Part 26: Electrostatic discharge (ESD) sensitivity testing - Human body model (HBM)*

IEC 61340 (all parts), *Electrostatics*

QC 001002 (all parts), *IEC Quality Assessment Systems for Electronic Components (IECQ) - Rules of procedure*

ISO 9000, *Quality management systems - Fundamentals and vocabulary*